

DUAL FREQUENCY CRYSTAL OSCILLATOR (XO) (10 MHz to 1.4 GHz)

Features

- Available with any-frequency output <a> Internal fixed crystal frequency frequencies from 10 MHz to 945 MHz and select frequencies to 1.4 GHz
- Two selectable output frequencies
- 3rd generation DSPLL® with superior jitter performance
- 3x better frequency stability than SAW-based oscillators
- ensures high reliability and low aging
- Available CMOS, LVPECL. LVDS, and CML outputs
- 3.3. 2.5. and 1.8 V supply options
- Industry-standard 5 x 7 mm package and pinout
- Pb-free/RoHS-compliant



Applications

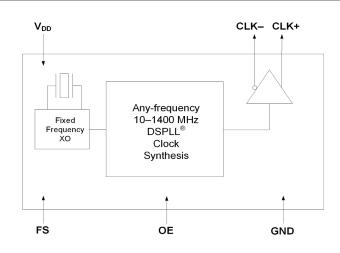
- SONET/SDH
- Networking
- SD/HD video

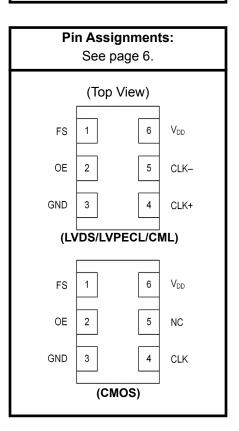
- Test and measurement
- Clock and data recovery
- FPGA/ASIC clock generation

Description

The Si532 dual frequency XO utilizes Silicon Laboratories' advanced DSPLL® circuitry to provide a low jitter clock at high frequencies. The Si532 is available with any-frequency output frequency from 10 to 945 MHz and select frequencies to 1400 MHz. Unlike a traditional XO where a different crystal is required for each output frequency, the Si532 uses one fixed crystal frequency to provide a wide range of output frequencies. This IC based approach allows the crystal resonator to provide exceptional frequency stability and reliability. In addition, DSPLL clock synthesis provides superior supply noise rejection, simplifying the task of generating low jitter clocks in noisy environments typically found in communication systems. The Si532 IC based XO is factory configurable for a wide variety of user specifications including frequency, supply voltage, output format, and temperature stability. Specific configurations are factory programmed at time of shipment, thereby eliminating long lead times associated with custom oscillators.

Functional Block Diagram





1. Electrical Specifications

Table 1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Supply Voltage ¹	V _{DD}	3.3 V option	2.97	3.3	3.63	V
		2.5 V option	2.25	2.5	2.75	V
		1.8 V option	1.71	1.8	1.89	V
Supply Current	I _{DD}	Output enabled LVPECL CML LVDS CMOS	_ _ _ _	111 99 90 81	121 108 98 88	mA
		Tristate mode	_	60	75	mA
Output Enable (OE)		V _{IH}	0.75 x V _{DD}	_	_	V
and Frequency Select (FS) ²		V _{IL}	_	_	0.5	V
Operating Temperature Range	T _A		-40	_	85	°C

Notes:

- 1. Selectable parameter specified by part number. See Section 3. "Ordering Information" on page 7 for further details.
- 2. OE and FS pins include a 17 $k\Omega$ pullup resistor to V_{DD} . Pulling OE to ground causes outputs to tristate.

Table 2. CLK± Output Frequency Characteristics

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Nominal Frequency ^{1,2}	f _O	LVPECL/LVDS/CML	10	_	945	MHz
		CMOS	10	_	160	MHz
Initial Accuracy	f _i	Measured at +25 °C at time of shipping	_	±1.5	_	ppm
Temperature Stability ^{1,3}			-7 -20 -50	_ _ _	+7 +20 +50	ppm
Aging	f	Frequency drift over first year	_	_	±3	ppm
	f _a	Frequency drift over 20 year life	_	_	±10	ppm
Total Stability		Temp stability = ±7 ppm	_	_	±20	ppm
		Temp stability = ±20 ppm	_	_	±31.5	ppm
		Temp stability = ±50 ppm	_	_	±61.5	ppm

Notes

- 1. See Section 3. "Ordering Information" on page 7 for further details.
- 2. Specified at time of order by part number. Also available in frequencies from 970 to 1134 MHz and 1213 to 1417 MHz.
- 3. Selectable parameter specified by part number.
- 4. Time from powerup or tristate mode to f_O.



Table 2. CLK± Output Frequency Characteristics (Continued)

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Powerup Time ⁴	tosc		_	_	10	ms
Settling Time After FS Change	t _{FRQ}		_	_	10	ms

Notes:

- 1. See Section 3. "Ordering Information" on page 7 for further details.
- 2. Specified at time of order by part number. Also available in frequencies from 970 to 1134 MHz and 1213 to 1417 MHz.
- **3.** Selectable parameter specified by part number.
- **4.** Time from powerup or tristate mode to f_O.

Table 3. CLK± Output Levels and Symmetry

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
LVPECL Output Option ¹	V _O	mid-level	V _{DD} – 1.42	_	V _{DD} – 1.25	V
	V _{OD}	swing (diff)	1.1	_	1.9	V_{PP}
	V _{SE}	swing (single-ended)	0.55	_	0.95	V _{PP}
LVDS Output Option ²	V _O	mid-level	1.125	1.20	1.275	V
	V _{OD}	swing (diff)	0.5	0.7	0.9	V _{PP}
CML Output Option ²	W	2.5/3.3 V option mid-level	_	V _{DD} – 1.30	_	V
	V _O	1.8 V option mid-level	_	V _{DD} – 0.36	_	V
	V	2.5/3.3 V option swing (diff)	1.10	1.50	1.90	V_{PP}
	V _{OD}	1.8 V option swing (diff)	0.35	0.425	0.50	V _{PP}
CMOS Output Option ³	V _{OH}	I _{OH} = 32 mA	0.8 x V _{DD}	_	V_{DD}	V
	V _{OL}	I _{OL} = 32 mA	_	_	0.4	
Rise/Fall time (20/80%)	t _{R,} t _F	LVPECL/LVDS/CML	_	_	350	ps
		CMOS with C _L = 15 pF	_	1	_	ns
Symmetry (duty cycle)	SYM		45	_	55	%

Notes:

- **1.** 50 Ω to V_{DD} 2.0 V. **2.** R_{term} = 100 Ω (differential). **3.** C_L = 15 pF



Table 4. CLK± Output Phase Jitter

Parameter	Symbol	Test Condition	Min	Тур	Max	Units
Phase Jitter (RMS) ¹	фЈ	12 kHz to 20 MHz (OC-48)		0.25	0.40	ps
for F _{OUT} ≥ 500 MHz		50 kHz to 80 MHz (OC-192)	_	0.26	0.37	ps
Phase Jitter (RMS) ¹	фЈ	12 kHz to 20 MHz (OC-48)	_	0.36	0.50	ps
for F _{OUT} of 125 to 500 MHz		50 kHz to 80 MHz (OC-192) ²		0.34	0.42	ps
Phase Jitter (RMS)	фЈ	12 kHz to 20 MHz (OC-48) ²	_	0.62		ps
for F _{OUT} of 10 to 160 MHz CMOS Output Only		50 kHz to 20 MHz ²	_	0.61	_	ps

Notes:

- **1.** Refer to AN256 for further information.
- 2. Max offset frequencies: 80 MHz for FOUT \geq 250 MHz, 20 MHz for 50 MHz \leq FOUT <250 MHz, 2 MHz for 10 MHz \leq FOUT <50 MHz.

Table 5. CLK± Output Period Jitter

Parameter	Symbol	Test Condition	Min	Тур	Max	Units	
Period Jitter*	J _{PER}	RMS	_	2	_	ps	
		Peak-to-Peak		14		ps	
*Note: Any output mode, including CMOS, LVPECL, LVDS, CML. N = 1000 cycles. Refer to AN279 for further information.							

Table 6. CLK± Output Phase Noise (Typical)

Offset Frequency (f)	120.00 MHz LVDS	156.25 MHz LVPECL	622.08 MHz LVPECL	Units
100 Hz 1 kHz 10 kHz 100 kHz 1 MHz 10 MHz	-112 -122 -132 -137 -144 -150 n/a	-105 -122 -128 -135 -144 -147 n/a	-97 -107 -116 -121 -134 -146 -148	dBc/Hz

Table 7. Environmental Compliance

The Si532 meets the following qualification test requirements.

Parameter	Conditions/Test Method
Mechanical Shock	MIL-STD-883, Method 2002
Mechanical Vibration	MIL-STD-883, Method 2007
Solderability	MIL-STD-883, Method 2003
Gross & Fine Leak	MIL-STD-883, Method 1014
Resistance to Solder Heat	MIL-STD-883, Method 2036
Moisture Sensitivity Level	J-STD_020, MSL1
Contact Pads	Gold over Nickel

Table 8. Thermal Characteristics

(Typical values TA = 25 °C, V_{DD} = 3.3 V)

Parameter	Symbol	Test Condition	Min	Тур	Max	Unit
Thermal Resistance Junction to Ambient	$\theta_{\sf JA}$	Still Air	_	84.6	_	°C/W
Thermal Resistance Junction to Case	θЈС	Still Air	_	38.8	_	°C/W
Ambient Temperature	T _A		-40	_	85	°C
Junction Temperature	T _J		_	_	125	°C

Table 9. Absolute Maximum Ratings¹

Parameter	Symbol	Rating	Units
Maximum Operating Temperature	T _{AMAX}	85	°C
Supply Voltage, 1.8 V Option	V _{DD}	-0.5 to +1.9	V
Supply Voltage, 2.5/3.3 V Option	V_{DD}	-0.5 to +3.8	V
Input Voltage (any input pin)	V _I	-0.5 to V _{DD} + 0.3	V
Storage Temperature	T _S	-55 to +125	°C
ESD Sensitivity (HBM, per JESD22-A114)	ESD	2500	V
Soldering Temperature (Pb-free profile) ²	T _{PEAK}	260	°C
Soldering Temperature Time @ T _{PEAK} (Pb-free profile) ²	t _P	20–40	seconds

Notes:

- 1. Stresses beyond those listed in Absolute Maximum Ratings may cause permanent damage to the device. Functional operation or specification compliance is not implied at these conditions.
- 2. The device is compliant with JEDEC J-STD-020C. Refer to Si5xx Packaging FAQ available for download at www.silabs.com/VCXO for further information, including soldering profiles.



2. Pin Descriptions

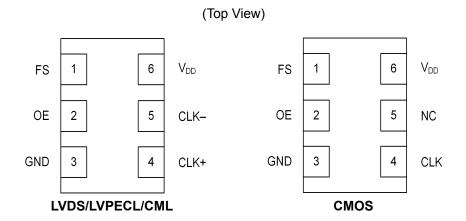


Table 10. Pin Descriptions

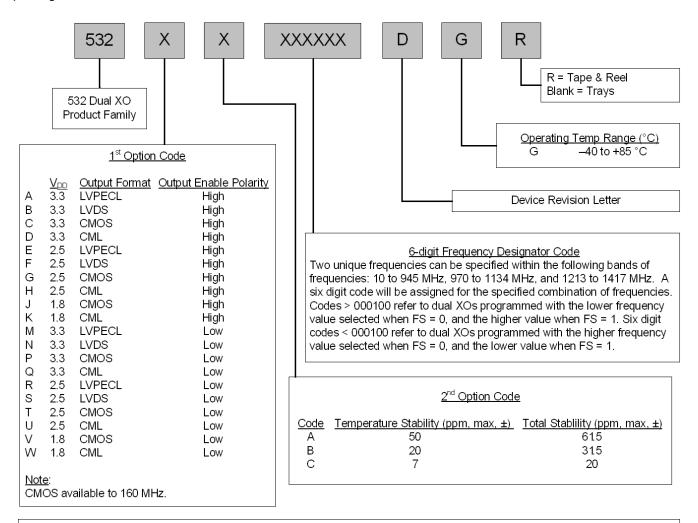
Pin	Symbol	LVDS/LVPECL/CML Function	CMOS Function
1	FS*	Frequency Select 0 = First frequency selected 1 = Second frequency selected	Frequency Select 0 = First frequency selected 1 = Second frequency selected
2	OE*	Output enable 0 = clock output disabled (outputs tristated) 1 = clock output enabled	Output enable 0 = clock output disabled (outputs tristated) 1 = clock output enabled
3	GND	Electrical and Case Ground	Electrical and Case Ground
4	CLK+	Oscillator Output	Oscillator Output
5	CLK-	Complementary Output	No connection
6	V _{DD}	Power Supply Voltage	Power Supply Voltage

*Note: FS and OE include a 17 $k\Omega$ pullup resistor to V_{DD} . See Section 3. "Ordering Information" for details on frequency value ordering.



3. Ordering Information

The Si532 XO supports a variety of options including frequency, temperature stability, output format, and V_{DD} . Specific device configurations are programmed into the Si532 at time of shipment. Configurations can be specified using the Part Number Configuration chart below. Silicon Laboratories provides a web browser-based part number configuration utility to simplify this process. Refer to www.silabs.com/VCXOPartNumber to access this tool and for further ordering instructions. The Si532 is supplied in an industry-standard, RoHS-compliant, 6-pad, 5 x 7 mm package.



Example Part Number: 532AB000108DGR is a 5×7 mm Dual XO in a 6 pad package. Since the six digit code (000108) is > 000100, f0 is 644.53125 MHz (lower frequency) and f1 is 693.48299 (higher frequency), with a 3.3 V supply, LVPECL output, and Output Enable active high polarity. Temperature stability is specified as ± 20 ppm. The part is specified for a -40 to ± 40 to ± 40 mbient temperature range operation and is shipped in tape and reel format.

Figure 1. Part Number Convention



4. Outline Diagram and Suggested Pad Layout

Figure 2 illustrates the package details for the Si532. Table 11 lists the values for the dimensions shown in the illustration.

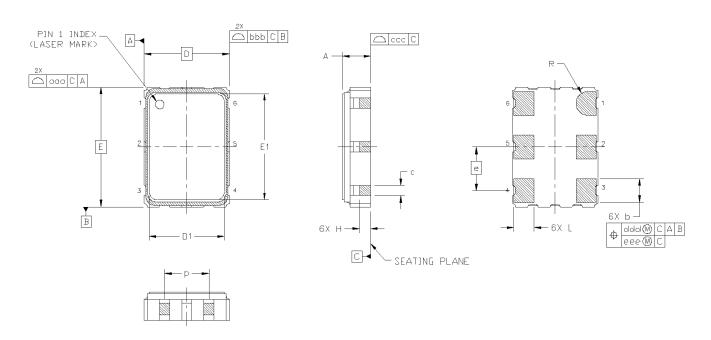


Figure 2. Si532 Outline Diagram

Table 11. Package Diagram Dimensions (mm)

Dimension	Min	Nom	Max		
A	1.50	1.65	1.80		
b	1.30	1.40	1.50		
С	0.50	0.60	0.70		
D		5.00 BSC			
D1	4.30	4.40	4.50		
е		2.54 BSC			
E		7.00 BSC			
E1	6.10	6.20	6.30		
Н	0.55	0.65	0.75		
L	1.17	1.27	1.37		
р	1.80	_	2.60		
R		0.70 REF			
aaa		0.15			
bbb	0.15				
ccc	0.10				
ddd	0.10				
eee		0.05			

5. Si532 Mark Specification

Figure 3 illustrates the mark specification for the Si532. Table 12 lists the line information.

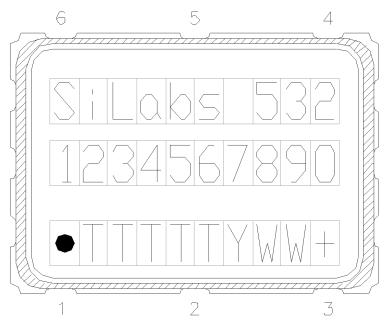


Figure 3. Mark Specification

Table 12. Si53x Top Mark Description

Line	Position	Description		
1	1–10	"SiLabs 532"		
2	1–10	Si532: Option1 + Option2 + ConfigNum(6) + Temp		
3	Trace Code			
	Position 1	Position 1 Pin 1 orientation mark (dot)		
	Position 2	sition 2 Product Revision (D)		
	Position 3–6	Tiny Trace Code (4 alphanumeric characters per assembly release instructions)		
	Position 7 Year (least significant year digit), to be assigned by assembly site (
	Position 8–9	Calendar Work Week number (1–53), to be assigned by assembly site		
	Position 10	"+" to indicate Pb-Free and RoHS-compliant		



9

6. 6-Pin PCB Land Pattern

Figure 4 illustrates the 6-pin PCB land pattern for the Si532. Table 13 lists the values for the dimensions shown in the illustration.

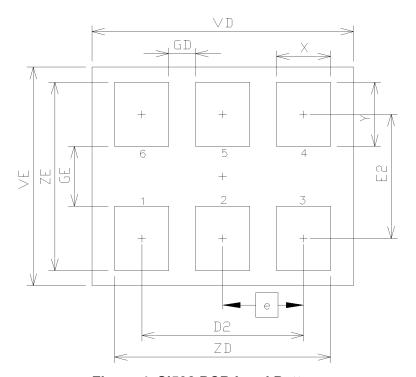


Figure 4. Si532 PCB Land Pattern

Table 13. PCB Land Pattern Dimensions (mm)

Dimension	Min	Max	
D2	5.08 REF		
е	2.54 BSC		
E2	4.15 REF		
GD	0.84	_	
GE	2.00	_	
VD	8.20 REF		
VE	7.30 REF		
X	1.70 TYP		
Y	2.15 REF		
ZD	-	6.78	
ZE	_	6.30	

Notes:

- 1. Dimensioning and tolerancing per the ANSI Y14.5M-1994 specification.
- 2. Land pattern design based on IPC-7351 guidelines.
- 3. All dimensions shown are at maximum material condition (MMC).
- 4. Controlling dimension is in millimeters (mm).



DOCUMENT CHANGE LIST

Revision 1.0 to Revision 1.1

- Updated Table 1, "Recommended Operating Conditions," on page 2.
 - Device maintains stable operation over –40 to +85 °C operating temperature range.
 - Supply current specifications updated for revision D.
- Updated Table 2, "CLK± Output Frequency Characteristics," on page 2.
 - Added specification for ±20 ppm lifetime stability (±7 ppm temperature stability) XO.
- Updated Table 3, "CLK± Output Levels and Symmetry," on page 3.
 - Updated LVDS differential peak-peak swing specifications.
- Updated Table 4, "CLK± Output Phase Jitter," on page 4.
- Updated Table 5, "CLK± Output Period Jitter," on page 4.
 - Revised period jitter specifications.
- Updated Table 9, "Absolute Maximum Ratings¹," on page 5 to reflect the soldering temperature time at 260 °C is 20–40 sec per JEDEC J-STD-020C.
- Updated 3. "Ordering Information" on page 7.
 - Changed ordering instructions to revision D.
- Added 5. "Si532 Mark Specification" on page 9.

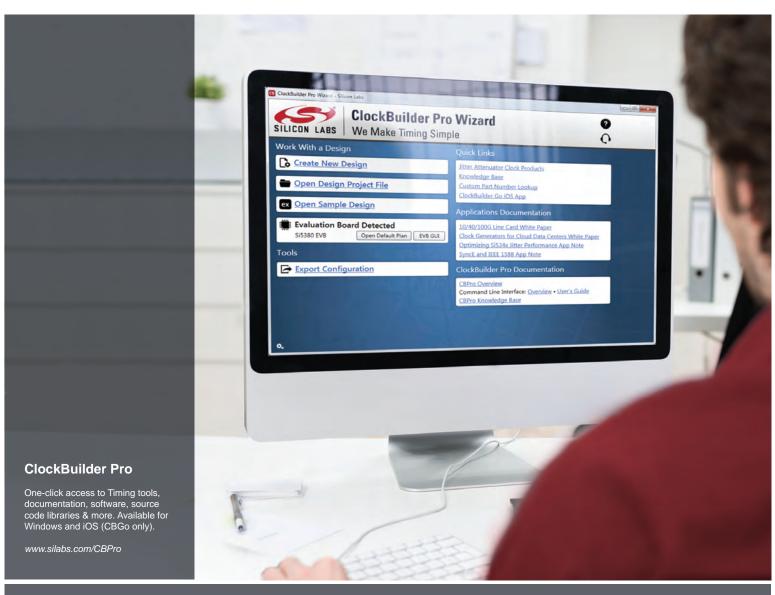
Revision 1.1 to Revision 1.2

- Updated 2.5 V/3.3 V and 1.8 V CML output level specifications for Table 3 on page 3.
- Added footnotes clarifying max offset frequency test conditions for Table 4 on page 4.
- Removed the words "Differential Modes: LVPECL/LVDS/CML" in the footnote referring to AN256 in Table 4 on page 4.
- Added CMOS phase jitter specs to Table 4 on page 4.
- Updated Table 7 on page 5 to include the "Moisture Sensitivity Level" and "Contact Pads" rows.
- Revised Figure 2 on page 8 to reflect current package outline diagram.
- Updated Figure 3 and Table 12 on page 9 to reflect specific marking information. Previously, Figure 3 was generic.

Revision 1.2 to Revision 1.3

Added Table 8, "Thermal Characteristics," on page 5.













Disclaimer

Silicon Laboratories intends to provide customers with the latest, accurate, and in-depth documentation of all peripherals and modules available for system and software implementers using or intending to use the Silicon Laboratories products. Characterization data, available modules and peripherals, memory sizes and memory addresses refer to each specific device, and "Typical" parameters provided can and do vary in different applications. Application examples described herein are for illustrative purposes only. Silicon Laboratories reserves the right to make changes without further notice and limitation to product information, specifications, and descriptions herein, and does not give warranties as to the accuracy or completeness of the included information. Silicon Laboratories shall have no liability for the consequences of use of the information supplied herein. This document does not imply or express copyright licenses granted hereunder to design or fabricate any integrated circuits. The products must not be used within any Life Support System without the specific written consent of Silicon Laboratories. A "Life Support System" is any product or system intended to support or sustain life and/or health, which, if it fails, can be reasonably expected to result in significant personal injury or death. Silicon Laboratories products are generally not intended for military applications. Silicon Laboratories products shall under no circumstances be used in weapons of mass destruction including (but not limited to) nuclear, biological or chemical weapons, or missiles capable of delivering such weapons.

Trademark Information

Silicon Laboratories Inc., Silicon Laboratories, Silicon Labs, SiLabs and the Silicon Labs logo, CMEMS®, EFM, EFM32, EFR, Energy Micro, Energy Micro logo and combinations thereof, "the world's most energy friendly microcontrollers", Ember®, EZLink®, EZMac®, EZRadio®, EZRadioPRO®, DSPLL®, ISOmodem ®, Precision32®, ProSLIC®, SiPHY®, USBXpress® and others are trademarks or registered trademarks of Silicon Laboratories Inc. ARM, CORTEX, Cortex-M3 and THUMB are trademarks or registered trademarks of ARM Holdings. Keil is a registered trademark of ARM Limited. All other products or brand names mentioned herein are trademarks of their respective holders.



Silicon Laboratories Inc. 400 West Cesar Chavez Austin, TX 78701 USA